

PATENT NUMBER and  
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10080424	02/22/2002	438	166	2812	COLEMAN

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\*\*CONTINUING DATA VERIFIED:

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\*\* FOREIGN APPLICATIONS VERIFIED:  
JAPAN 2001-47181 02/22/2001

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>	
Foreign priority claimed 35 USC 119 conditions met Verified and Acknowledged Examiner's initials		<input type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> yes <input type="checkbox"/> no	ATTORNEY DOCKET NO YKI-0084
TITLE : Method for manufacturing polycrystalline semiconductor layers and thin-film transistors, and laser annealing apparatus			
U.S. DEPT. OF COMM./PAT. & TM-PTO-436L(Rev. 12-94)			

NOTICE OF ALLOWANCE MAILED		Assistant Examiner	CLAIMS ALLOWED	
Amount Due	Date Paid		Total Claims	Print Claim for O.G.
ISSUE FEE		Primary Examiner	DRAWING	
TERMINAL DISCLAIMER			Sheets Drwg.	Figs.Drwg.
PREPARED FOR ISSUE		Application Examiner		
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